


<b>Search Notes</b>  	<b>Application/Control No.</b>  10676819	<b>Applicant(s)/Patent Under Reexamination</b>  WEDEL ET AL.
	<b>Examiner</b>  Chen, Qing	<b>Art Unit</b>  2191

### SEARCHED

Class	Subclass	Date	Examiner
717	100-103,110-113	6/17/2010	/QC/
714	19	6/17/2010	/QC/
715	700,771	6/17/2010	/QC/
345	666	6/17/2010	/QC/

### SEARCH NOTES

Search Notes	Date	Examiner
Updated EAST Search (US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM TDB) -- See Search History Printout	6/17/2010	/QC/
717/100-103,110-113; 714/19; 715/700,771; 345/666 (limited class search using keywords)	6/17/2010	/QC/
Updated EAST Inventor Name Search and Assignee Search (US-PGPUB; USPAT) -- See Search History Printout	6/17/2010	/QC/
Updated PALM Inventor Name Search	6/17/2010	/QC/
Consulted SPE Wei Zhen (AU 2191)	6/17/2010	/QC/

### INTERFERENCE SEARCH

Class	Subclass	Date	Examiner
717	100-103,110-113	6/17/2010	/QC/
714	19	6/17/2010	/QC/
715	700,771	6/17/2010	/QC/
345	666	6/17/2010	/QC/

--	--